# **PART NO.** MVR0402-240E100

## 1. Electrical Specification

#### 1-1 Test condition

In = 1 mA DCVaristor voltage Vdc = 24 V DCLeakage current Ic = 1 A

Maximum clamping voltage

Rated peak single pulse transient current  $8/20 \,\mu s$  waveform, +/- each 1 time induce

Capacitance 10/1000  $\mu s$  waveform Insulation resistance after reflow soldering f = 1MHz, Vrms = 0.5 V

Soldering paste: Tamura (Japan) RMA-20-21L

Stencil: SUS, 120  $\mu$ m thickness

Reflow soldering condition Pad size: 0.5 (Width) x 0.6 (Length)

0.5 (Distance between pads)

Soldering profile : 260 $\pm 5$  °C, 5 sec.

### 1-2 Electrical specification

Maximum allowable continuous DC voltage	24	V	
trigger voltage / Varistor voltage / breakdown voltage	23-32	V	
Maximum clamping voltage	60	V	Maximum
Rated peak single pulse transient current	1	Α	Maximum
Nonlinearity coefficient	> 12		
Leakage current at continuous DC voltage	< 0.1	μA	
Response time	< 0.5	ns	
Varistor voltage temperature coefficient	< 0.05	%/℃	
Capacitance measured at 1MHz	10	pF	Typical
Capacitance tolerance	-30 to +30	%	
Insulation resistance after reflow soldering on PCB	> 10	$\mathbf{M}\Omega$	
Operating ambient temperature	-55 to +125	${\mathbb C}$	
Storage temperature	-55 to +125	${}^{\mathbb{C}}$	

## 1-3 Reliability testing procedures

Reliability parameter	Test	Test methods and remarks	Test requirement	
Pulse current capability	lmax 8/20 μs	IEC 1051-1, Test 4.5.  10 pulses in the same direction at 2 pulses per minute at maximum peak current	d   Vn   /Vn ≤ 10% no visible damage	
Electrostatic discharge capability	ESD C=150 pF, R=330 Ω	IEC 1000-4-2  Each 10 times in positive/negative direction in 10 sec at 8KV contact discharge (Level 4)	d   Vn   /Vn ≤ 10% no visible damage	
Environmenta I reliability	Thermal shock	IEC 68-2-14  Condition for 1 cycle Step 1 : Min40°C, 30±3 min. Step 2 : Max. +125°C, 30±3 min.  Number of cycles: 30 times	d   Vn   /Vn ≤ 5% no visible damage	
	Low temperature	Harmser of cycles. 30 times	d   Vn   /Vn ≤ 5% no visible damage	
	High temperature	IEC 68-2-2  Place the chip at $125\pm5$ °C for $1000\pm24$ hrs. Remove and place for $24\pm2$ hrs at room temp. condition, then measure	d   Vn   /Vn ≤ 5% no visible damage	
	Heat resistance	IEC 68-2-3 Apply the rated voltage for $1000\pm48 hrs$ at $85\pm3\%$ . Remove and place for $24\pm2 hrs$ at room temp. condition, then measure	d   Vn   /Vn ≤ 5% no visible damage	
	Humidity resistance	IEC 68-2-30 Place the chip at $40\pm2\%$ and 90 to 95% humidity for $1000\pm24$ hrs. Remove and place for $24\pm2$ hrs at room temp. condition, then measure	d   Vn   /Vn ≤ 10% no visible damage	
	Pressure cooker test	Place the chip at 2 atm, 120 °C, 85%RH for 60 hrs. Remove and place for 24 ± 2hrs at room temp. condition, then measure	d   Vn   /Vn ≤ 10% no visible damage	
	Operating life	Apply the rated voltage for $1000 \pm 48$ hrs at $125 \pm 3^{\circ}$ C. Remove and place for $24 \pm 2$ hrs at room temp. condition, then measure	d   Vn   /Vn ≤ 10% no visible damage	

Mechanical	Solderability	IEC 68-2-58	At least 95% of terminal
Reliability		Solder bath method, 230 $\pm$ 5 $^{\circ}\mathrm{C}$ , 2s	electrode is covered by new solder
	Resistance to	IEC 68-2-58	d   Vn   /Vn ≤ 5%
soldering heat	Solder bath method, $260\pm5$ °C, $10\pm0.5$ s, $270\pm5$ °C, $3\pm0.5$ s	no visible damage	
	Bending strength	IEC 68-2-21	$dVn /Vn \le 5\%$
		Warp:2mm, Speed:0.5mm/sec, Duration: 10sec. The measurement shall be made with board in the bent position	no visible damage
	Adhesive strength	IEC 68-2-22	Strength>10 N
		Applied force on SMD chip by fracture from PCB	no visible damage

# 2. Material Specification

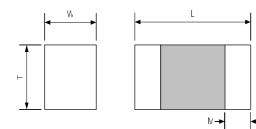
Body ZnO based ceramics

Internal electrode Silver – Palladium

External electrode Silver – Nickel – Tin

Thickness of Ni/Sn plating layer Nickel  $> 1 \mu m$ , Tin  $> 2 \mu m$ 

# 3. Dimension Specification

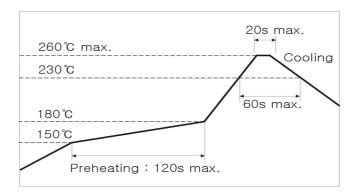


Size	L(mm)	W(mm)	T(mm)	M(mm)
0402	$1.0 \pm 0.10$	$0.5 \pm 0.10$	≤ 0.6	$0.20 \pm 0.10$
0603	1.6±0.15	$0.8 \pm 0.15$	≤ 0.9	$0.35 \pm 0.10$

## 4. Soldering Recommendations

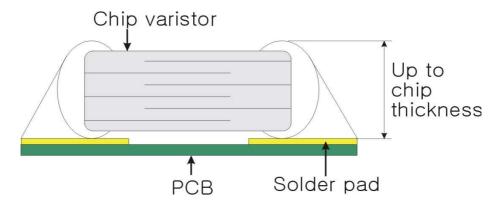
## 4-1 Soldering profile

### 4-1-1 Pb free solder paste



### 4-1-2 Repair soldering

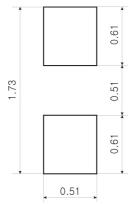
- Allowable time and temperature for making correction with a soldering iron : 350  $\pm$  10  $^{\circ}$ C, 3 sec.
- Optimum solder amount when corrections are made using a soldering iron



## 4-2 Soldering guidelines

- Our chip varistors are designed for reflow soldering only. Do not use flow soldering
- Use non-activated flux (CI content 0.2% max.)
- Follow the recommended soldering conditions to avoid varistor damage.

### 4-3 Solder pad layout



## 5. Storage condition

- Storage environment must be at an ambient temperature of 25~35  $\,^\circ\!\mathbb{C}\,$  and an ambient humidity of 40~60 % RH
- Chip varistors can experience degradation of termination solderability when subjected to high temperature of humidity, or if exposed to sulfur or chlorine gases.
- Avoid mechanical shock (ex. Falling) to the chip varistor to prevent mechanical cracking inside of the ceramic dielectric due to its own weight.
- Use chips within 6 months.
   If 6 months of more have elapsed, check solderability before use.-

### 6. Description about package label

#### Type: MVR0402-240E100

MVR: Series name

0402 : Chip size -0402 (1.0 x 0.5 mm) size

240 : Maximum continuous working voltage – 24Vdc

E: Product function - E for ESD

100 : Capacitance value - means 10pF

#### Qunatity: 10,000 pcs

- Quantity of shipping chip varistor